



# PERRY JOHNSON LABORATORY ACCREDITATION, INC.

## Certificate of Accreditation

*Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:*

### **Creation Technologies Analysis & Testing LLC**

**1450 Mission Avenue, Albuquerque, NM 87107**

*(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:*

### **ISO/IEC 17025:2017**

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system  
(as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017)

***Creation Technologies Analysis & Testing LLC provides testing, failure analysis, counterfeit avoidance, and screening of electronic components***

*(As detailed in the supplement)*

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen  
President

*Initial Accreditation Date:*

August 16, 2018

*Issue Date:*

April 2, 2022

*Expiration Date:*

April 2, 2024

*Accreditation No.:*

102178

*Certificate No.:*

L22-220

Perry Johnson Laboratory  
Accreditation, Inc. (PJLA)  
755 W. Big Beaver, Suite 1325  
Troy, Michigan 48084

*The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: [www.pjllabs.com](http://www.pjllabs.com)*



# Certificate of Accreditation: Supplement

## Creation Technologies Analysis & Testing LLC

1450 Mission Avenue, Albuquerque, NM 87107  
 Contact Name: Cory Hunter Phone: 208-350-3309

Accreditation is granted to the facility to perform the following testing:

FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED	RANGE (WHERE APPROPRIATE) AND DETECTION LIMIT
Acoustical <sup>F</sup>	Electrical, Electronic and Electromechanical (EEE) Components	Acoustic Microscopy (CSAM) Examination/ Inspection	IPC/JEDEC J-STD-035	15 MHz to 75 MHz
	Suspect/Counterfeit EEE Part Detection	Acoustic Microscopy (CSAM) Examination/ Inspection	SAE AS6171/6	15 MHz to 75 MHz
Chemical <sup>F</sup>	Suspect/Counterfeit EEE Part Detection	Remarking/Resurfacing	SAE AS6171/2	Visual Evaluation
		De-capsulation and Die Verification	SAE AS6171/4 Chemical De-capsulation, Mechanical Disassembly Plasma, Reactive Ion Etching	
Environmental <sup>F</sup>	Electrical, Electronic and Electromechanical (EEE) Components	Exposure/Temperature Cycling	MIL-STD-883, TM 1010 MIL-STD-750, TM 1051	Low: -75 °C (-103 °F) High: 175 °C (347 °F)
Mechanical <sup>F</sup>	Polymers, Non-volatile Residue, Material Electrical, Electronic and Electromechanical (EEE) Components	Material Characterization	ASTM E334	48 Hz to 63 Hz
	Suspect/Counterfeit EEE Parts Detection	SEM Examination Internal/External Visual	SAE AS6171/2	Low Mag 30 x to 2 000 x High Mag 100 x to 800 000 x
		Material Characterization	AS6171/9	48 Hz – 63 Hz
	Electrical, Electronic and Electromechanical (EEE) Components	Fine Leak Testing Leak Rate	MIL-STD-883, Method 1014 Condition A <sup>1</sup> MIL-STD-750, Method 1071 Condition H <sup>1</sup> MIL-STD-202, Method 112 Condition C, Procedure IIIa	Detecting Instrument Limit = 10-8 cc/sec
SEM Examination/Inspection		MIL-STD-750, Method 2077 MIL-STD-883, Method 2018 MIL-STD-1580, Method 9.2, 9.3	Low Mag 30 x to 2 000 x High Mag 100 x to 800 000 x Prohibited Materials	



# Certificate of Accreditation: Supplement

## Creation Technologies Analysis & Testing LLC

1450 Mission Avenue, Albuquerque, NM 87107  
Contact Name: Cory Hunter Phone: 208-350-3309

Accreditation is granted to the facility to perform the following testing:

FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED	RANGE (WHERE APPROPRIATE) AND DETECTION LIMIT
Mechanical <sup>F</sup>	Electrical, Electronic and Electromechanical (EEE) Components	Particle Impact Noise Detection (PIND)	MIL-STD-883, Method 2020 MIL-STD-750, Method 2052	Vibration 0.1 g in to 25.5 g in amplitude; 27 Hz -250 Hz Freq displacement of 0.25" Shock 200 g to 2 000 g w/ pulse width of 100 ms
		Die Shear Grams and Force	MIL-STD-883, Method 2019 MIL-STD-750, Method 2037	Up to 5 kgf
		Wire Pull	MIL-STD-883, Method 2011 MIL-STD-750, Method 2037	Up to 100 gf
		Gross Leak Testing Examination/Inspection	MIL-STD-883, Method 1014, Condition D MIL-STD-750, Method 1071, Condition C & D MIL-STD-202, Method 112, Condition E	Visual Evaluation
		Internal Examination/Inspection	MIL-STD-883, Method 2010, 2013, 2017, and 2032 MIL-STD-750, Method 2069, 2070, 2072 and 2074	Z20 x 20 to Z100 x 1 000



# Certificate of Accreditation: Supplement

## Creation Technologies Analysis & Testing LLC

1450 Mission Avenue, Albuquerque, NM 87107  
Contact Name: Cory Hunter Phone: 208-350-3309

Accreditation is granted to the facility to perform the following testing:

FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED	RANGE (WHERE APPROPRIATE) AND DETECTION LIMIT
Non-Destructive <sup>F</sup>	Electrical, Electronic and Electromechanical (EEE) Components	Elemental content by XRF, EDS (Lead, tin, etc.)	JESD213 ASTM B568 MIL-STD-1580, Method 9.1, 9.3	Presence/Absence Prohibited Materials
		Elemental thickness XRF (ENIG)	IPC-4552	
		Radiographic Examination/Inspection	MIL-STD-883, Method 2012 (excluding sections 2.1, 3.2.1, 3.2.2, 3.3.1.1, 3.3.1.2, 3.4.1.1 a & b, 3.4.1.2 a & b, 3.5, 3.8, 3.9) MIL-STD-750, Method 2076 (excluding sections 2.1, 3.1) MIL-STD-202, Method 209 (excluding sections 3.2, 4.2, 4.4, 5.1.2, & 5.2.2)	
	Suspect/Counterfeit EEE Part Detection	Elemental content by XRF, EDS	SAE AS6171/3	
		Radiographic Examination/Inspection	SAE AS6171/5	

1. The presence of a superscript F means that the laboratory performs testing of the indicated parameter at its fixed location. Example: Outside Micrometer<sup>F</sup> would mean that the laboratory performs this testing at its fixed location.